# SEM analysis of structures with Mo iris run at CTF3 .

CLIC meeting 30/06/2006

#### Introduction.





#### Background:

- Iris-in-copper-disc structures.
- Mo iris, fired at 800 °C.
- Run in CTF3 2005, 30 GHz.
- Run history presented by Roberto, see next slide.

#### Analyses:

- Surface SEM + EDS for first and last cavities.
- Compared to other structures run in CTFII and SLAC.





High-gradient Test Results of the 30 GHz Mo-Iris Structure Alberto Rodriguez. CLIC Meeting - 3 February 2006

#### Conditioning: Effective time





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High-gradient Test Results of the 30 GHz Mo-Iris Structure Alberto Rodriguez CLIC Meeting - 3 February 2006

#### Calibration uncertainty



With Faraday cup event (in red)



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### Contents.

#### Intro.

Surface modifications.

- Overview and comparison with historical structures.
- Details of worst region.
- Comparison of different irises along the structure.
- Comparison of different radial positions within one iris.

#### Cu wall

#### Surface composition. Contamination/cleaning





# Surface modification in tip region 1<sup>st</sup> iris. Comparison SLAC / CTFII / CTF3 runs.





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# Surface modification in tip region. Comparison historic structures / CTF3 run.

CTF3 Mo 1st

#### First Cu cavity run in CTFII.

Presentation of 12/04/2001.

SLAC 1<sup>st</sup> Presentation of 13/02/2004

#### Firs Richard In CTI Presentation of 19/11



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### Surface modifications. Overview of worst region: tip of 1<sup>st</sup> iris.



Very **sharp** and **high** peaks. Different that what has been observed so far in DC spark craters.

Clusters of craters are not always localized on top of the peaks.





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#### Surface modifications. Comparison of irises along the structure.





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## Surface modifications. Comparison of irises along the structure.









Localized clusters of craters.

Craters coexist with smoothly eroded surface. Two different phenomena?





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Smooth protrusions but uniform, no craters.







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200x



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1<sup>st</sup> reverse side

No craters or particular intense smoothening around the embedded SiC particles





100 um



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### Surface modifications. Close to the Cu wall, 1<sup>st</sup> iris.





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## Surface contamination/cleaning. Comparison along radial locations 1<sup>st</sup> iris.

Ref.: Si peak from SiC embedded particles, no Cu peak

- 1: reduced Si, significant presence of Cu
- 2: absence of Si, presence of Cu
- 3: absence of Si, slight presence of Cu

• Copper contamination. The closer to the wall the higher.

Si (from SiC particles) disappeared.



EDS analysis: —: spectra at the given points --: reference spectrum from a ground surface not exposed to RF

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## Surface contamination/cleaning. Comparison along radial locations 1<sup>st</sup> reverse.





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# Surface contamination/cleaning. 30<sup>th</sup> iris.

30<sup>th</sup> 2 51 damaged first irises? Full line : CTF3-2005-Iris30- g5 (20/03/2006 17:21) Full line : CTF3-2005-Iris30- p4 (20/03/2006 17:15) Dashed line : CTF3-2005-Iris1+ ref. (20/03/2006 14:53) Dashed line : CTF3-2005-Iris1+ ref. (20/03/2006 14:53) cps cps 50 50 40 40 30-30 Cu 20 20 Mc 10 10 Mo 1000x 20 un 0



